



## IFPRI BRIEF TEMPLATE

Check One:    Project                       Review                       Collaboration  
                    Workshop                       Other

<b>Descriptive Title</b>	Smart in-situ pressure sensor particles for process characterization.
<b>Working Title<sup>1</sup></b>	Smart sensor particles
<b>Technical Area<sup>2</sup></b>	Characterization
<b>Date</b>	6/25/2019
<b>Short Description</b>	Use of particles as measures of “real” in-line process conditions (e.g. Pressure, Stress, Force)
<b>Objectives</b>	<ul style="list-style-type: none"> <li>• Identify range of measurable peak pressures, forces, stresses using a micronized smart particle probe</li> <li>• Review the science behind the use of persistent responses such as fluorescent emission (or X-ray/Raman/near-IR/other) under applied force/stress field</li> <li>• List examples of candidate particles and sizes</li> <li>• List detection methodology/science</li> <li>• State the challenges and future outlook</li> </ul> <p><u>Long range objective (beyond this review):</u> Identify or make “smart” fine particles for experimentally evaluating a process? For example, these particles would be used to diagnose peak pressure in a tableting operation, an extruder, a granulator, a pump, a reactor.</p>
<b>Scope</b>	<p>Particles responsive to pressure and/or stress and/or force via emission of light, radiation, X-ray and/or other detectable signal. Particles finer than 100 microns are within scope. Piezochromic coatings are also within scope.</p> <p>Out of scope: Coarse photoelastic particles with reversible birefringence (IFPRI understands these well)          Out of scope: Particle position tracking methods such as PEPT          Out of scope: Analyses that require high power difficult-to-access resources (e.g. neutron scattering)</p>

<b>Recommended Contractors (2 or 3)</b>		
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<sup>1</sup> Title used in meeting agendas and file archives

<sup>2</sup> One or more from the following list: W = wet systems; D = dry systems; F = particle formation; SR = size reduction; M = modeling; SE = systems engineering

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